

Notice of References Cited	Application/Control No. 10/698,222	Applicant(s)/Patent Under Reexamination SHI ET AL.	
	Examiner Toan M. Le	Art Unit 2863	Page 1 of 1

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	B	US-6,597,193	07-2003	Lagowski et al.	324/765
	C	US-5,528,153	06-1996	Taylor et al.	324/671
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NON-PATENT DOCUMENTS

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	U	Schroder, Contactless Surface Charge Semiconductor Characterization, April 2002, Materials Science and Engineering B, Vol. 91-92, Pages 196-228
	V	Schroder et al., Corona-Oxide-Semiconductor Device Characterization, 1998, Solid-State Electronics, Vol. 42, No. 4, Pages 505-512
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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